

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/605,289	LIPSON ET AL.	
Examiner		Sheela C Chawan	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,324,298 B1	11-2001	O'Dell et al.	382/149
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Reinholt Geelink et al. " unified feature definition for feature based design and feature based manufacturing ". University of Twente Department of Mechanical Engineering Laboratory of Production and Design Engineering Enschede, The Netherlands.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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